Application/Control No. 10/040,556 Applicant(s)/Patent Under Reexamination TAKAYAMA ET AL. Examiner Daniel St.Cyr Applicant(s)/Patent Under Reexamination TAKAYAMA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-4523087	06-1985	Benton	235/379
	В	US-5461217	10-1995	Claus	235/379
	С	US-5650604	07-1997	Marcous et al	235/379
	D	US-5691525	11-1997	Aoki et al	235/379
	E	US-5949044	09-1999	Walker et al	235/379
	F	US-6488203	12-2002	Stoutenburg et al	235/379
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

TOTAL SOCIETY						
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